


<b>Search Notes</b> 	<b>Application/Control No.</b> 10528340	<b>Applicant(s)/Patent Under Reexamination</b> MATSUI ET AL.
	<b>Examiner</b> RICHARD CHAN	<b>Art Unit</b> 2618

SEARCHED			
Class	Subclass	Date	Examiner
455	450, 464, 509, 154.1, 526	6/8/08	RC
370	431, 437, 458,	6/8/08	RC

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

--	--